

April 1988 Revised September 2000

74F38

Quad Two-Input NAND Buffer (Open Collector)

General Description

This device contains four independent gates, each of which performs the logic NAND function. The open-collector outputs require external pull-up resistors for proper logical operation.

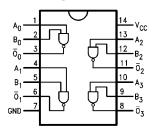
Ordering Code:

Order Number	Package Number	Package Description
74F38SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
74F38SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F38PC	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol

Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L. HIGH/LOW	Input I _{IH} /I _{IL} Output I _{OH} /I _{OL}		
A _n , B _n	Inputs	1.0/2.0	20 μA/–1.2 mA		
\overline{O}_n	Outputs	OC (Note 1) /106.6	OC (Note 1) /64 mA		

Note 1: OC = Open Collector

Function Table

Inputs		Output		
Α	В	0		
L	L	Н		
L	Н	Н		
Н	L	Н		
Н	Н	L		

H = HIGH Voltage Level L = LOW Voltage Level

Absolute Maximum Ratings(Note 2)

-65°C to +150°C

Storage Temperature -55°C to +125°C Ambient Temperature under Bias Junction Temperature under Bias $-55^{\circ}C$ to $+150^{\circ}C$

V_{CC}Pin Potential to Ground Pin -0.5V to +7.0VInput Voltage (Note 3) -0.5V to +7.0VInput Current (Note 3) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC} 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0° C to +70°C Supply Voltage +4.5V to +5.5V

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: Either voltage limit or current limit is sufficient to protect inputs.

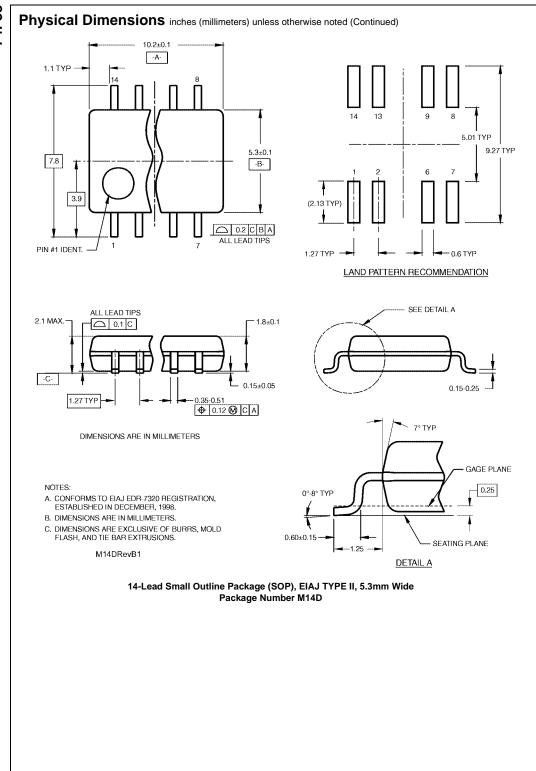
DC Electrical Characteristics

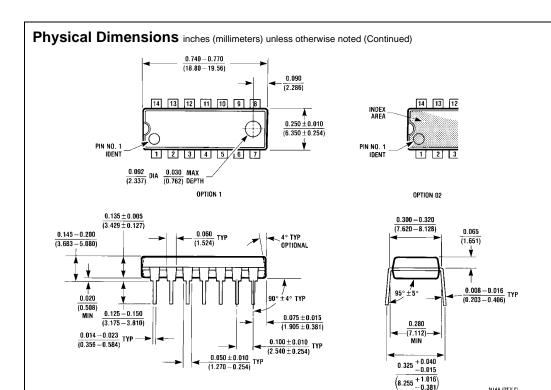
Symbol	Parameter	Min	Тур	Max	Units	v _{cc}	Conditions	
V _{IH}	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal	
V _{IL}	Input LOW Voltage			0.8	V		Recognized as a LOW Signal	
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = -18 mA	
V _{OL}	Output LOW 10% V _{CC}			0.55	V	Min	I _{OL} = 64 mA	
	Voltage							
I _{IH}	Input HIGH			5.0	μА	Max	V _{IN} = 2.7V	
	Current			3.0	μΛ	IVIGA	V IN - 2.1 V	
I _{BVI}	Input HIGH Current			7.0	μА	Max	V _{IN} = 7.0V	
	Breakdown Test						VIN = 7.5 V	
V _{ID}	Input Leakage	4.75			V	0.0	$I_{ID} = 1.9 \mu A$	
	Test	4.73			v	0.0	All Other Pins Grounded	
I _{OD}	Output Leakage			3.75	μА	0.0	V _{IOD} = 150 mV	
	Circuit Current						All Other Pins Grounded	
I _{IL}	Input LOW Current			-1.2	mA	Max	V _{IN} = 0.5V	
I _{OHC}	Open Collector, Output			250	μА	Min	V - V	
	OFF Leakage Test						$V_{OUT} = V_{CC}$	
I _{CCH}	Power Supply Current		2.1	7.0	mA	Max	V _O = HIGH	
I _{CCL}	Power Supply Current		26.0	30.0	mA	Max	$V_O = LOW$	

AC Electrical Characteristics

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	
t _{PLH}	Propagation Delay	6.5	9.7	12.5	6.5	13.0	ns
t _{PHL}	A_n , B_n to \overline{O}_n	1.5	2.1	5.0	1.5	5.5	115

14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow Package Number M14A





14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N14A

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N14A (REV F)